

Search Notes

Application/Control No.

10/642,790

Examiner

Randall Chin

Applicant(s)/Patent under
Reexamination

MURAKAMI, TAKEHIKO

Art Unit

1744

SEARCHED

| Class | Subclass | Date | Examiner |
|-------|----------|-----------|----------|
| 15 | 1 | | |
| 15 | 3 | | |
| 101 | 423 | | |
| 101 | 424 | 8/20/2005 | RC |
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INTERFERENCE SEARCHED

| Class | Subclass | Date | Examiner |
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**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

| | DATE | EXMR |
|------------------------------|-----------|------|
| EAST, OCR, DERWENT, EPO, JPO | 8/20/2005 | RC |
| Inventor name search | 8/20/2005 | RC |
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